Power MOSFET 30 V, 1.15 mΩ, 230 A, Single N–Channel Logic Level, SO–8FL

Features

- Small Footprint (5x6 mm) for Compact Design
- Low R_{DS(on)} to Minimize Conduction Losses
- Low Q_G and Capacitance to Minimize Driver Losses
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

MAXIMUM RATINGS	$(1_{\rm J} = 25^{\circ})$	J unless otherv	vise noted)		
Parameter		Symbol	Value	Unit	
Drain-to-Source Voltage		V _{DSS}	30	V	
Gate-to-Source Voltage		V _{GS}	±20	V	
$\begin{array}{c} \text{Continuous Drain Current } R_{\theta JC} \text{ (Notes 1, 2, 3)} \end{array}$	Steady State	T _C = 25°C	Ι _D	230	A
Power Dissipation $R_{\theta JC}$ (Notes 1, 2)	Olale	$T_C = 25^{\circ}C$	P _D	96	W
$\begin{array}{c} \mbox{Continuous Drain Current } R_{\theta JA} \ (\mbox{Notes 1, 2, } 3) \end{array}$	Steady State	T _A = 25°C	Ι _D	41	A
Power Dissipation $R_{\theta JA}$ (Notes 1, 2)	Slale	T _A = 25°C	P _D	3.13	W
Pulsed Drain Current	$T_A = 25^\circ C$, $t_p = 10 \ \mu s$		I _{DM}	388	А
Operating Junction and Storage Temperature		T _J , T _{stg}	-55 to 150	°C	
Source Current (Body Diode) @ 10 ms		I _S	128	А	
Single Pulse Drain–to–Source Avalanche Energy $(I_{L(pk)} = 61 \text{ A})$		E _{AS}	186	mJ	
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)		ΤL	260	°C	
Change and an and a diam the same	Para di la r	L Martin D		and a state of a second	

MAXIMUM RATINGS (T_{.1} = 25°C unless otherwise noted)

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL RESISTANCE MAXIMUM RATINGS (Note 1)

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State (Note 2)	$R_{\theta JC}$	1.3	°C/W
Junction-to-Ambient - Steady State (Note 2)	R_{\thetaJA}	40	

1. The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.

2. Surface-mounted on FR4 board using a 650 $\rm mm^2,$ 2 oz. Cu pad.

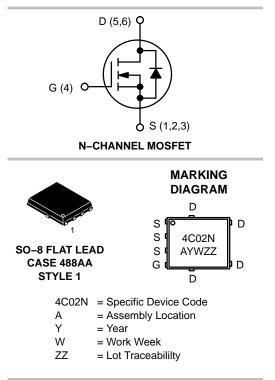
3. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



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V _{(BR)DSS}	R _{DS(on)} MAX	I _D MAX
30 V	1.15 mΩ @ 10 V	230 A
30 V	1.7 mΩ @ 4.5 V	230 A



ORDERING INFORMATION

Device	evice Package	
NTMFS4C302NT1G	SO–8 FL (Pb–Free)	1500 / Tape & Reel

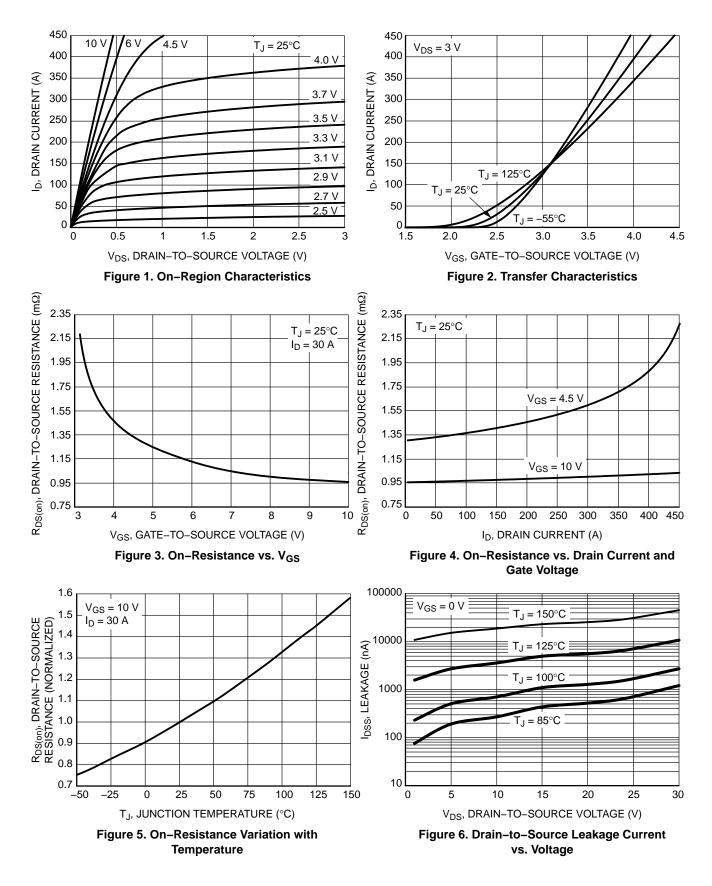
+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

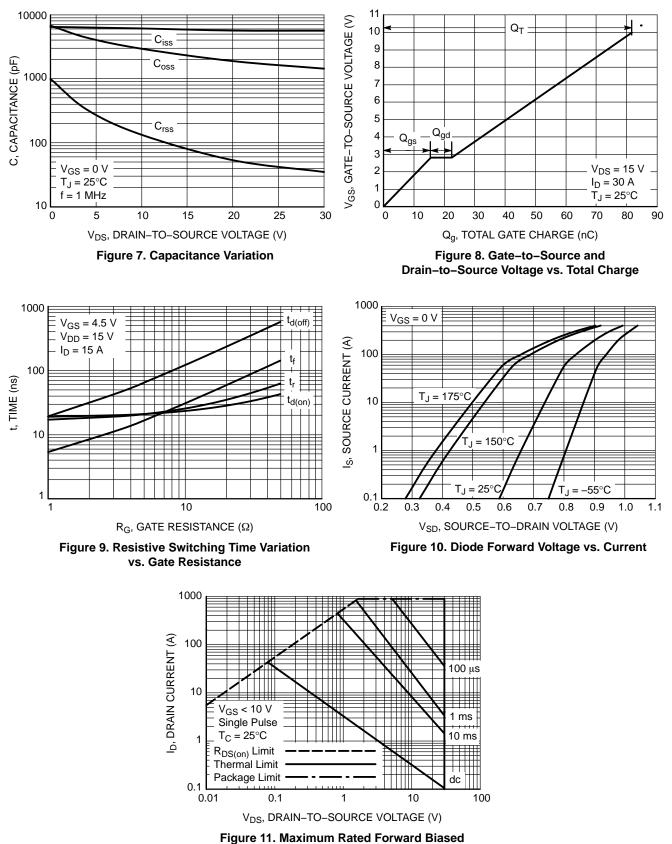
Parameter	Symbol	Test Cond	lition	Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 V, I_D = 250 \mu A$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} / T _J				24		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V, V _{DS} = 24 V	T _J = 25 °C			1.0	μΑ
			T _J = 125°C			100	
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS} = 20 V				100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_{D}$	= 250 μA	1.3		2.2	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				5.8		mV/°
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 30 A		0.95	1.15	mΩ
		V _{GS} = 4.5 V	I _D = 30 A		1.35	1.7	
Forward Transconductance	9FS	V _{DS} = 3 V, I _E	₀ = 30 A		135		S
Gate Resistance	R _G	T _A = 25 °C			0.75		Ω
CHARGES AND CAPACITANCES				-			
Input Capacitance	C _{ISS}				5780		1
Output Capacitance	C _{OSS}	V_{GS} = 0 V, f = 1 MHz, V_{DS} = 15 V			2320		pF
Reverse Transfer Capacitance	C _{RSS}				70		
Total Gate Charge	Q _{G(TOT)}				37		<u> </u>
Threshold Gate Charge	Q _{G(TH)}	V _{GS} = 4.5 V, V _{DS} = 15 V; I _D = 30 A			9.0		nC
Gate-to-Source Charge	Q _{GS}				16		
Gate-to-Drain Charge	Q _{GD}				7.0		1
Total Gate Charge	Q _{G(TOT)}	V_{GS} = 10 V, V_{DS} = 15 V, I _D = 30 A			82		nC
SWITCHING CHARACTERISTICS (Note 5)				-			
Turn–On Delay Time	t _{d(ON)}				20		
Rise Time	t _r	V_{GS} = 4.5 V, V_{DS} = 15 V, I_D = 15 A, R _G = 3.0 Ω			19		ns
Turn-Off Delay Time	t _{d(OFF)}				42		
Fall Time	t _f				11		
DRAIN-SOURCE DIODE CHARACTERISTIC	S						
Forward Diode Voltage	V _{SD}	$V_{GS} = 0 V_{CS}$	$T_J = 25^{\circ}C$		0.75	1.1	V
		V _{GS} = 0 V, I _S = 10 A	T _J = 125°C		0.6		
Reverse Recovery Time	t _{RR}	V _{GS} = 0 V, dI _S /dt = 100 A/µs, I _S = 30 A			56		ns
Charge Time	t _a				29		
Discharge Time	t _b				27		
Reverse Recovery Charge	Q _{RR}				69		nC

performance may not be indicated by the Electrical Characteristics for the listed test conditions, to 4. Pulse Test: pulse width $\leq 300 \ \mu$ s, duty cycle $\leq 2\%$. 5. Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS



TYPICAL CHARACTERISTICS



Safe Operating Area

TYPICAL CHARACTERISTICS

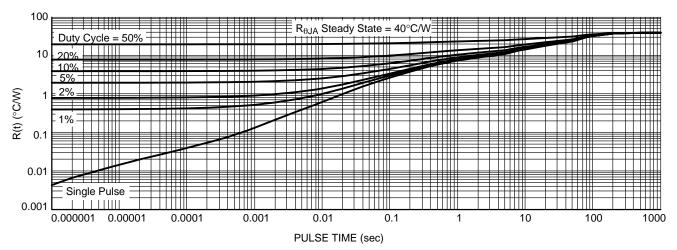
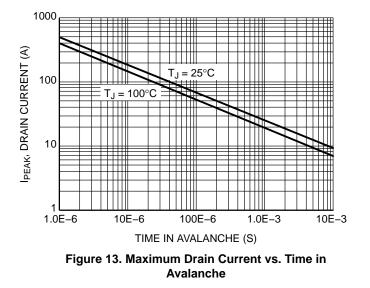
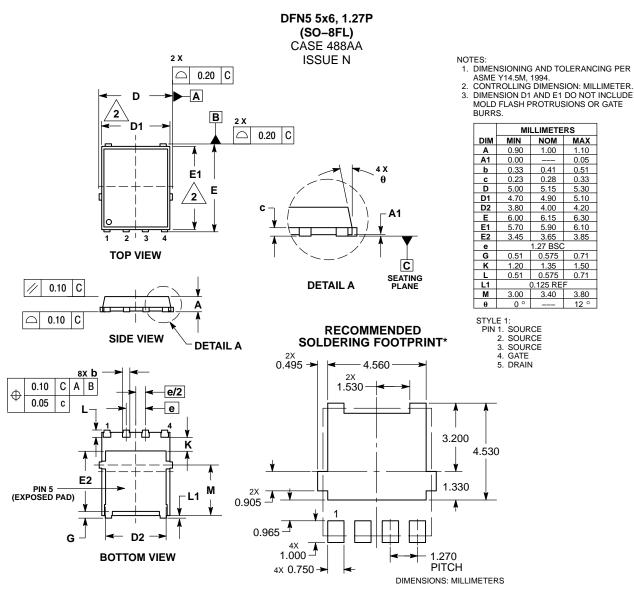


Figure 12. Thermal Response



PACKAGE DIMENSIONS



*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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